

[SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE AND DEVICE FOR TESTING SAME]

Abstract of Disclosure

A device for testing a semiconductor integrated circuit device has a test board on which the semiconductor integrated circuit device to be tested is removably mounted, and a two-pulse generator mounted on the test board, for generating two pulses spaced from each other by a pulse interval equal to the period of a test clock for the delay test, from the test clock, and supplying the generated two pulses to the scan path test circuit. The device also has a PLL circuit for multiplying the frequency of the test clock and supplying a signal having the multiplied-frequency to the two-pulse generator.